

FIG. 1

$V_{fb}$  (V) vs.  $TOX$  (Å) for Al/20Å\_TiN Gate

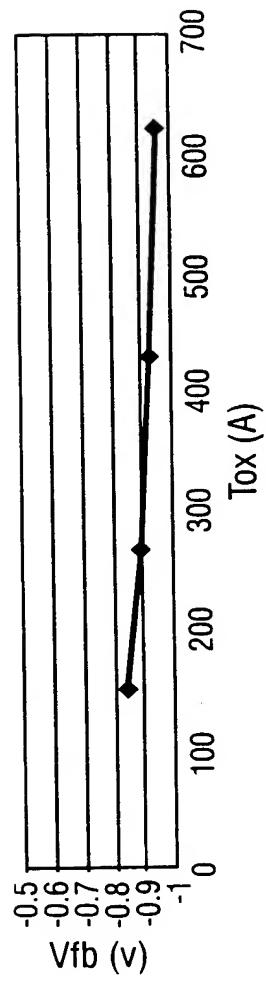


FIG. 2

Work-Function of Al/TiN Gate Changes  
as the thickness of thin TiN changes

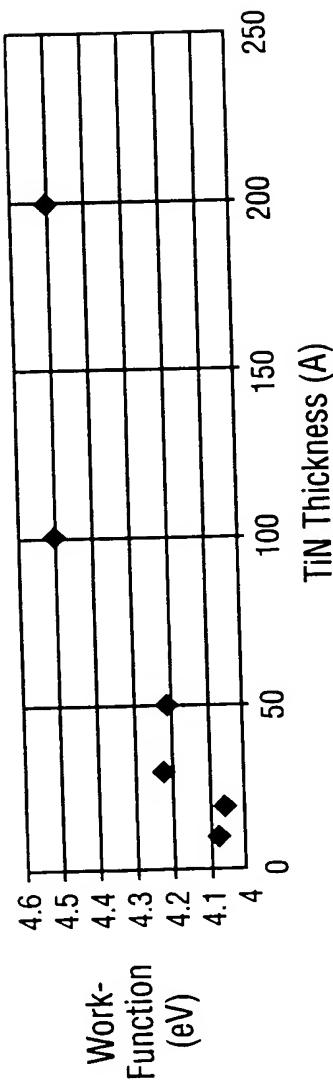


FIG. 3

$V_t(V)$  for various gate stack with different TiN thickness

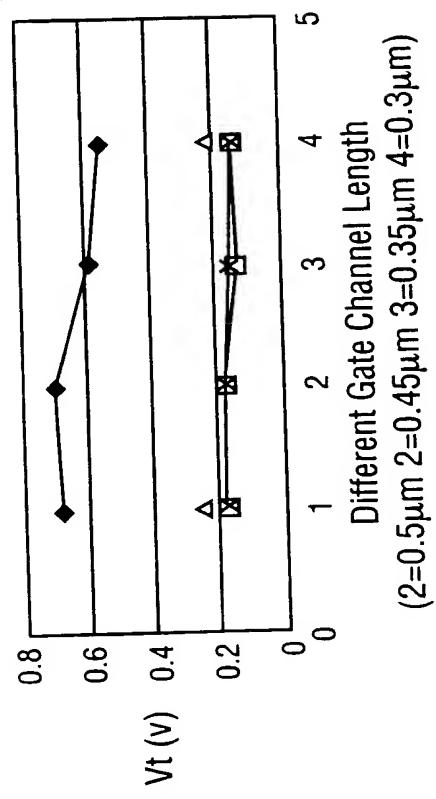
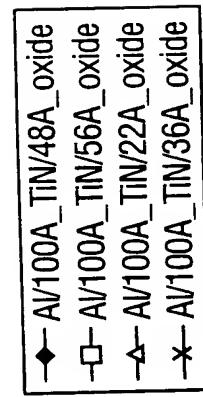


FIG. 4

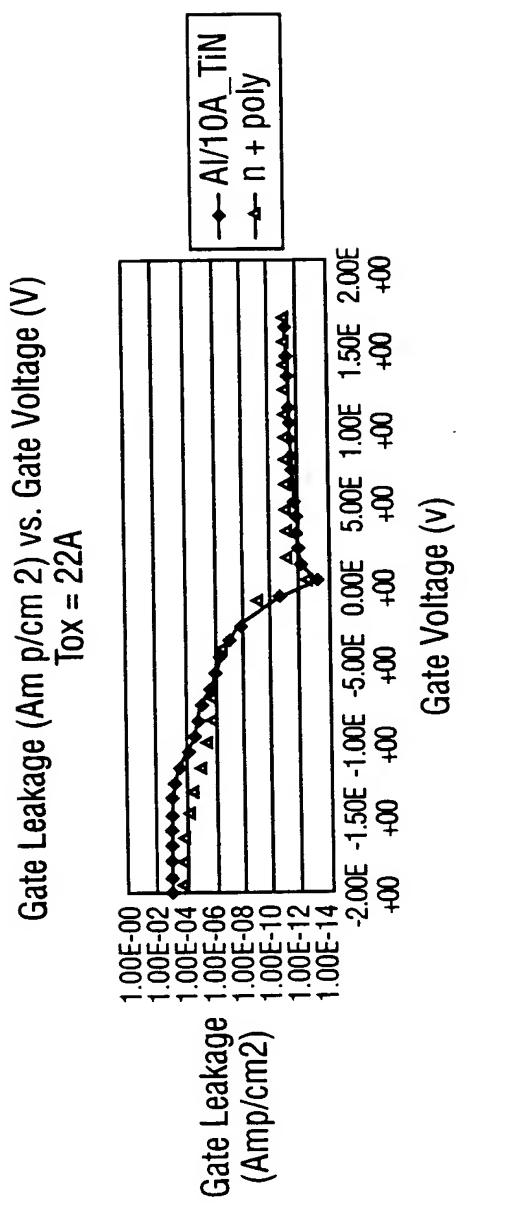


FIG. 5

QuasiStatic/High Frequency Capacitor Voltage  
Curves for A1/20 A\_TIN/50A Oxide  
Gate Stack

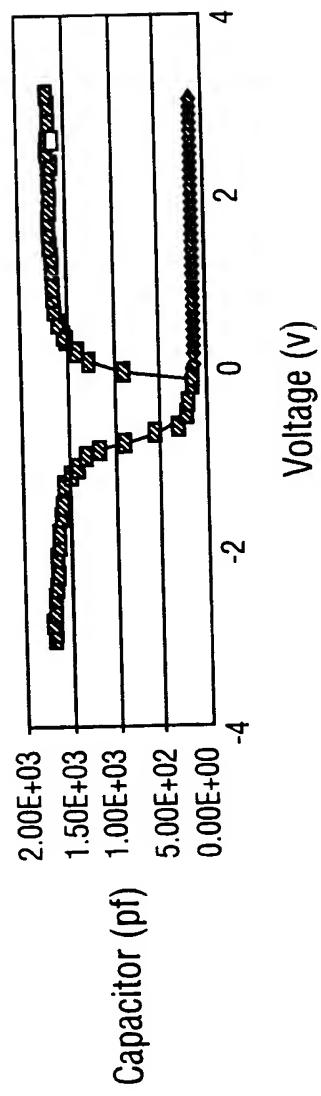


FIG. 6

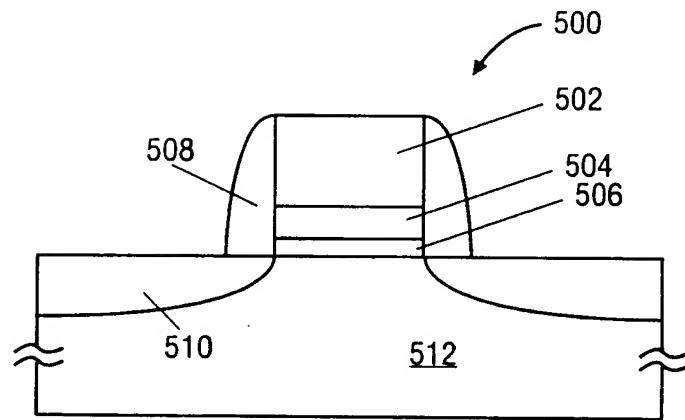


FIG. 7

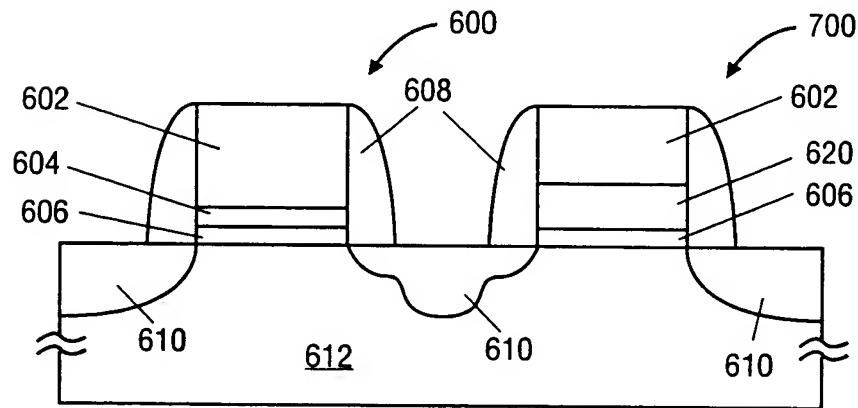


FIG. 8